


<b>Search Notes</b>  	<b>Application/Control No.</b>  10806420	<b>Applicant(s)/Patent Under Reexamination</b>  SHIN ET AL.
	<b>Examiner</b>  Riyami, Abdullah	<b>Art Unit</b>  2416

SEARCHED			
Class	Subclass	Date	Examiner
370	349, 395.31, 401, 466	7/23/2007	AR
370	312, 331, 338, 392	7/24/2007	AR
370	338, 349	2/1/2008	AR
370	329, 338, 340, 349, 400, 401, 406	11/22/2008	AR
370	310,310.2,313,328,331,338,349,392	6/2/2009	AR
455	432.1,435.1,435.1,436,456.1	6/2/2009	AR

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with SPE Dang Ton	7/23/2007	AR
Conducted EAST search	7/23/207	AR
Read IEEE articles related to subject matter	7/23/2007	AR
Updated East search	11/22/2008	AR
Updated East search	6/2/2009	AR
Consulted with SPE Aung Moe	6/2/2009	AR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/ABDULLAH RIYAMI/ Examiner.Art Unit 2416	
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